

## SLOVENSKI STANDARD oSIST FprEN 61000-4-21:2010

01-januar-2010

# Elektromagnetna združljivost (EMC) - 4-21. del: Preskusne in merilne tehnike - Preskusne metode za odbojne sobe

Electromagnetic compatibility (EMC) -- Part 4-21: Testing and measurement techniques - Reverberation chamber test methods

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## <u>SIST EN 61000-4-21:2011</u>

Ta slovenski standard je istoveten z: FprEN 61000-4-21:2009

### <u>ICS:</u>

33.100.01 Elektromagnetna združljivost Electromagnetic compatibility na splošno in general

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## 77B/619/CDV

#### COMMITTEE DRAFT FOR VOTE (CDV) PROJET DE COMITÉ POUR VOTE (CDV)

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Also of interest to the following committees Intéresse également les comités suivants CISPR/A			Supersedes docum Remplace le docum 77B/576/CD & 7	ent	
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aussi il est demandé aux comités nationaux de fournir leurs commentaires et votes au travers de leur comité miroir du SC 77B.				de their comments and votes via their	
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commentaires à leurs collègues des comités miroirs du SC 77B, qui alors fourniront une compilation consolidée			•	SC 77B mirror committees which then olidated compilation of comments to the	
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CEI pou	ention des Comités nationaux de la NELEC, est attirée sur le fait que c Ir vote (CDV) de Norme internation vote parallèle.	e projet de comité ale est soumis au	CENELEC, is draw Vote (CDV) for an	IEC National Committees, members of n to the fact that this Committee Draft for International Standard is submitted for parallel voting.	
Le	es membres du CENELEC sont invi système de vote en ligne du C			embers are invited to vote through the ELEC online voting system.	

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98 99		INTERNATIONAL ELECTROTECHNICAL COMMISSION		
100 101 102		ELECTROMAGNETIC COMPATIBILITY (EMC) –		
102		Part 4-21: Testing and measurement techniques –		
104		Reverberation chamber test methods		
105				
106				
107		FOREWORD		
108 109 110 111 112 113 114 115 116	1)	The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.		
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140 141 142 143	International Standard IEC 61000-4-21 has been prepared by subcommittee 77B: High- frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility, in co- operation with CISPR subcommittee A: Radio interference measurements and statistica methods.			
144 145		forms Part 4-21 of IEC 61000. It has the status of a basic EMC publication in accordance th IEC Guide 107.		
146	Th	e main changes with respect to the first edition of this standard are the following:		
147 148 149 150 151		<ul> <li>In Clause 8, the use and specifications of E-field probes for application to reverberation chambers has been added. Additional Notes refer to general aspects and procedures of probe calibrations. The specified range for linearity of the probe response is larger and covers an asymmetric interval compared to that for use in anechoic chambers (see Annex I of IEC 61000-4-3), because</li> </ul>		
152		• the fluctuations of nower and fields in reverberation chambers exhibit a larger		

152 the fluctuations of power and fields in reverberation chambers exhibit a larger 0 153 dynamic range, and

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• the chamber validation procedure is based on using maximum field values, as opposed to the field itself or its average value,

- respectively.
- 157 In Annex A, additional guidance and clarifications on the use of reverberation 158 chambers at relatively low frequencies of operation (i.e., close to the lowest usable 159 frequency of a given chamber) are given, and its implications on the estimation of field 160 uncertainty are outlined. Guidelines on cable-layout have been added. A rationale has been 161 added that explains the relaxation of the field uniformity requirement below 400 MHz, being a 162 compromise between scientific-technical and economical reasons when using chambers around 100 MHz. A first-order correction for the threshold value of the correlation coefficient at 163 relatively low numbers of tuner positions has been added. Issues regarding the use of non-164 165 equidistant tuner positions at low frequencies are discussed in an additional Note.
- 166 In Annex B, symmetric location of the field probes when the chamber exhibits • cylindrical symmetry has been disallowed, as such placement could otherwise yield a 167 false indication of field uniformity and chamber performance at different locations. The 168 169 difference between start frequency for chamber validation and lowest test frequency has been 170 clarified. The tuner sequencing for chamber validation and testing is now specified to be equal 171 in both cases. In sample requirements for chamber validation, emphasis is now on the 172 required minimum number of independent tuner steps to be used, whereas the minimum 173 recommended number of samples per frequency interval has been replaced with he number of independent samples that the tuner can provide per frequency, for use in case when the 174 175 chamber validation fails for the required minimum number.
- Annex C now contains more quantitative guidance on the setting of the maximum permissible stirring speeds that warrant quasi-static conditions of operation for chamber validation and testing. Consideration is given to all characteristic time scales of all components or subsystems of a measurement or test. Specific issues relating to chamber validation, immunity testing and bandwidth are addressed. Particular requirements for field probes when used with mode stirred operation are listed.
- In Annex D, a requirement for the EUT and equipment not to occupy more than 8 % of the total chamber volume in immunity testing has been added. The maximum number of frequency points and the formula to calculate these points have been generalized. A mandatory specification for including the measurement equipment, test plan and cable layout in the test report has been added to resolve any dispute in case of discrepancies, particularly for low-frequency immunity testing.
- Annex E has been extended with further guidance on the value of EUT directivity to be used in the estimation of radiated power and field. Extended estimates have been added for the maximum directivity of electrically large, anisotropically radiating EUTs and for radiated emissions in the presence of a ground plane. A mandatory specification for including the measurement equipment, test plan and cable layout in the test report has been added to resolve any dispute in case of discrepancies, particularly for low-frequency emissions testing.
- In Annex I, some clarifications on antenna efficiency measurements have been added.
- A new Annex K has been added that covers measurement uncertainty in reverberation chambers. The intrinsic field uncertainty for chamber validation, immunity and emissions measurements is quantified. Other contributors to measurement uncertainty are listed.

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#### 200 The text of this standard is based on the following documents:

FDIS	Report on voting
77B/ /FDIS	77B/ /RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

203 This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication will remain unchanged until the maintenance result date<sup>1)</sup> indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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<sup>1)</sup> The National Committees are requested to note that for this publication the maintenance result date is 2015.

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212	INTRODUCTION				
213 214	IEC 61000 is published in separate parts according to the following structure:				
215 216	Part 1: General				
217	Definitions, terminology				
218					
219 220	Part 2: Environment Description of the environment				
221	Classification of the environment				
222	Compatibility levels				
223					
224 225	Part 3: Limits Emission limits				
226 227	Immunity limits (in so far as they do not fall under the responsibility of the product committees)				
228					
229 230	Part 4: Testing and measurement techniques Measurement techniques				
231	Testing techniques STANDARD PREVIEW				
232					
233 234	Part 5: Installation and mitigation guidelines S. Iten . 21 Installation guidelines				
235	Mitigation methods and devices ETEN 61000-4-21:2011				
236					
237 238	Part 6: Generic standards en-61000-4-21-2011				
239 240	Part 9: Miscellaneous				
241	Each part is further subdivided into several parts, published either as international standards				

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: IEC 61000-6-1). 61000-4-21 Ed.2/CDV © IEC:200X - 9 -

## 245 ELECTROMAGNETIC COMPATIBILITY (EMC) –

# 247Part 4-21: Testing and measurement techniques –248Reverberation chamber test methods

249

246

#### 250

#### 251 **1 Scope**

This part of IEC 61000 considers tests of immunity and intentional or unintentional emissions for electric and/or electronic equipment and tests of screening effectiveness in reverberation chambers. It establishes the required test procedures for performing such tests. Only radiated phenomena are considered.

The objective of this part is to establish a common reference for using reverberation chambers to evaluate the performance of electric and electronic equipment when subjected to radio-frequency electromagnetic fields and for determining the levels of radio-frequency radiation emitted from electric and electronic equipment.

NOTE Test methods are defined in this part for measuring the effect of electromagnetic radiation on equipment and the electromagnetic emissions from equipment concerned. The simulation and measurement of electromagnetic radiation is not adequate for quantitative determination of effects. The defined test methods are organized with the aim to establish adequate reproducibility and repeatability of test results and qualitative analysis of effects.

This part of IEC 61000 does not intend to specify the tests to be applied to a particular apparatus or system. Its main aim is to give a general basic reference to all concerned product committees of the IEC. The product committees should select emission limits and test methods in consultation with CISPR. The product committees remain responsible for the appropriate choice of the immunity tests and the immunity test limits to be applied to their equipment. Other methods, such as those covered in IEC 61000-4-3 and CISPR-16-2-3&4 may be used in consultation with CISPR and TC77, if specified by product committees.

#### 272 2 Normative references

The following referenced documents are indispensable for the application of this document.
For dated references, only the edition cited applies. For undated references, the latest edition
of the referenced document (including any amendments) applies.

276 IEC 60050(161):1990, International Electrotechnical Vocabulary (IEV) – Chapter 161:
 277 Electromagnetic compatibility

278 IEC 60068-1, *Environmental testing – Part 1: General and guidance* 

IEC 61000-4-3, Electromagnetic compatibility (EMC) – Part 4-3: Testing and measurement
 techniques – Radiated, radio-frequency, electromagnetic field immunity test

1281 IEC 61000-4-6, *Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields* 

283 CISPR 16-1, Specification for radio disturbance and immunity measuring apparatus and 284 methods – Part 1: Radio disturbance and immunity measuring apparatus

285 CISPR 16-2, Specification for radio disturbance and immunity measuring apparatus and 286 methods – Part 2: Methods of measurement of disturbances and immunity

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#### 287 **3 Definitions and acronyms**

#### 288 3.1 Definitions

For the purposes of this part of IEC 61000-4, the following definitions together with those in IEC 60050(161) apply.

- 291
- 292 **3.1.1**
- 293 antenna

that part of a radio transmitting or receiving system which is designed to provide the required coupling between a transmitter or a receiver and the medium in which the radio wave propagates

- 297 [IEV 712-01-01]
- 298 NOTE For the purpose of this procedure, antennas are assumed to have an efficiency of 75 % or greater.

299

### 300 **3.1.2**

#### 301 electromagnetic (EM) wave

- a wave characterized by the propagation of a time-varying electromagnetic field and caused
   by acceleration of electric charges
- 304 [IEV 705-01-09, modified]
- 305

#### 306 3.1.3

#### 307 far field region

that region of the electromagnetic field of an antenna or unintentional radiator wherein the predominant components of the field are those which represent a propagation of energy and wherein the angular field distribution is essentially independent of the distance from the

- 311 antenna https://standards.iteh.ai/catalog/standards/sist/fe847d54-d1ba-477f-a14c-4cea3a136a95/sist-
- 312 NOTE 1 In the far field region, all the components of the electromagnetic field decrease in inverse proportion to the distance from the antenna.
- 314 NOTE 2 For a *broadside* antenna having a maximum overall dimension, *D*, which is large compared to the wave-
- 315 length,  $\lambda$ , the far field region is commonly taken to exist at distances greater than  $2D^2/\lambda$  from the antenna in the 316 direction of maximum radiation.
- 317 [IEV 712-02-92]
- 318 The region far from a source or aperture where the radiation pattern does not vary with 319 distance from the source.
- 320 [IEV 731-03-92]
- 321
- 322 **3.1.4**

#### 323 field strength

the magnitude of the electromagnetic field created at a given point by a radio transmitting system operating at a specified characteristic frequency with specified installation and modulation conditions

327 [IEV 705-08-31]

328 NOTE The term "electric field strength" (in V/m) or "magnetic field strength" (in A/m) is used according to whether 329 the magnitude of the electric or magnetic field, respectively, is measured. In the near-field region, the relationship 330 between the electric and magnetic field strength and distance depends on the specific configuration involved. The 331 power flux density of the field is similarly indeterminate.

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- 332 NOTE In the far zone, field strength is sometimes identified with power flux density *P*. For a plane wave in free
- 333 space,  $P = E^2 / \eta_{V}$ , where
- 334 *E* is the electric field strength, and
- 335  $\eta_V$  is the intrinsic impedance of free space, approximately equal to  $120\pi$  ohm.
- 336 **3.1.5**

#### 337 polarization

the property of a sinusoidal electromagnetic wave or field vector defined at a fixed point in
space by the direction of the electric field strength vector or of any specified field vector;
when this direction varies with time, the property may be characterized by the locus described
by the extremity of the considered field vector

- 342 [IEV 726-04-01]
- 343

344 **3.1.6** 

#### 345 reverberation chamber

- a room specially designed to have a very long reverberation time
- 347 [IEV 723-03-30]

(reverberation room) room having a long reverberation time, especially designed to make the field therein as diffuse as possible. The room consists of a shielded enclosure that is generally equipped with mechanical tuners/stirrers that change (stir) the boundary conditions within the enclosure and, thus, alter the structure of the electromagnetic fields within the enclosure

353 [IEV 801-31-13, modified]

#### SIST EN 61000-4-21:2011

- 354 NOTE 1 Reverberation rooms are used in particular for the measurement of absorption coefficients of materials and measurement of the power emitted by intentional or unintentional radiating sources.
- NOTE 2 Testing in a reverberation chamber can be described as a stochastic process in which the mechanical tuners/stirrers "stir" the "modes" inside the enclosure. Therefore, such a chambers is also called stirred-mode, mode-stirred or mode-tuned chamber.
- 359
- 360 **3.1.7**

#### 361 quality factor (Q) of a reverberation chamber

- 362 (quality factor) frequency-dependent measure of sharpness of the resonance, equal to  $2\pi$ 363 times the ratio of the maximum stored energy to the energy dissipated during one period
- 364 [IEV 151-15-46, modified]

365 measure of how well the chamber stores energy (see A.6[2]<sup>2</sup>). For a given chamber, Q varies 366 as a function of frequency and can be calculated using the following formula:

$$Q = \frac{16\pi^2 V}{\eta_{\text{Tx}} \eta_{\text{Rx}} \lambda^3} \left\langle \frac{P_{\text{AveRec}}}{P_{\text{input}}} \right\rangle$$
(4)

368 where

367

369 V is the chamber volume (in units  $m^3$ ),

- 370  $\lambda$  is the wavelength (in units m),
- $\begin{array}{ccc} 371 & (\langle P_{\text{AveRec}}/P_{\text{inpu}\rangle t}) & \text{is the ratio of the received power to the input power averaged over one} \\ 372 & \text{complete tuner/stirrer sequence (and, where applicable, averaged over all antenna locations and orientations),} \end{array}$

 $<sup>^{2)}</sup>$  Numbers in brackets refer to the reference documents in the respective annexes.

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374 375 376 377	$\eta_{Tx}$ and $\eta_{Rx}$	and Receive (Rx) antennas,	actors (dimensionless) for the Transmit (Tx) respectively. If manufacturer's data is not can be assumed to be 0,75 for log periodic rennas.		
378					
379 380 381 382 383	<b>3.1.8</b> <b>Q-bandwidth (<math>BW_Q</math>) of a reverberation chamber</b> a measure of the frequency range over which the modes in a reverberation chamber are correlated (see Clause A.2). The $BW_Q$ of a reverberation chamber can be calculated using the following formula:				
384		BW <sub>Q</sub> =	f/Q (5)		
385	where				
386	f is the frequenc	y (in units Hz),			
387	Q is the quality fa	ctor defined in 3.1.7.			
388					
389 390 391 392		of the equipment to initiate or s action which might result in a	sustain a required function, or the initiation of dverse consequences		
393	NOTE The criteria of functional acceptance have to be precisely specified.				
394 395	[IEV 303-17-79]				
396					
397 398 399	<b>3.1.10</b> //standards.iteh.ai/catalog/standards/sist/fe847d54-d1ba-477f-a14c-4cea3a136a95/sist- emission en-61000-4-21-2011 The phenomenon by which energy emanates from a source in the form of waves or particles.				
400	[IEV 702-02-03]				
401					
402 403 404 405		constructed from low-loss ele oundary conditions inside a rev	ectrically conductive material which alters the verberation chamber		
406 407 408 409 410 411 412 413	respect to the waveler tuning/stirring device w at the lowest useable resulting multi-mode e environment is statistic	ngth at the lowest useable frequency whose dimensions are significant frac frequency. When the chamber is ex electromagnetic environment can be cally uniform and statistically isotropic	enclosure with the smallest dimension being large with . The chamber is normally equipped with a mechanical tions of the chamber dimensions and of the wavelength xcited with RF energy, the boundary conditions of the altered by the mechanical tuner/stirrer. The resulting c (i.e., the energy arriving from all aspect angles with all iciently large number of positions of the mechanical		
414					
415 416 417	3.1.12 electromagnetic r one solution of Ma		g an electromagnetic field in a certain space		

- 418 domain and belonging to a family of independent solutions defined by specified boundary 419 conditions
- 420 [IEV 705-01-12]
- 421

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- 422 **3.1.13**
- 423 validation
- 424 process of confirming that a finalized instrumentation, control system (hardware and software)
   425 and test facility complies with all of its functional, performance and interface requirements
- 426 [IEV 394-40-42 (modified)]
- 427
- 428 **3.1.14**

#### 429 chamber validation

- process of confirming that a chamber complies with all of its functional, performance andinterface requirements
- 432 [IEV 394-40-42 (modified)]
- 433

434 **3.1.15** 

#### 435 intrinsic field uncertainty (IFU)

436 contribution to the overall uncertainty budget that is caused by the random (statistical) nature437 of the field inside a reverberation chamber

438

443

439 NOTE Typically, the intrinsic field uncertainty is considerably larger than the measurement instrumentation
 440 uncertainty in typical operation of a reverberation chamber, except when the chamber has an exceptionally high
 441 quality factor. As a result, the IFU is typically the only or main contribution to be considered in estimating the
 442 overall uncertainty during test or measurement.

#### 444 3.1.16

#### 445 working volume

region defined by 8 points inside the chamber at sufficient distance away from the walls to
avoid boundary effects, for rectangular chambers typically defined by the corners of a cubic or

parallelepiped region at quarter-wavelength distance from the nearest walls ca3a136a95/sist-

- 449
- $450 \qquad \text{NOTE} \ \ \text{For frequencies below 1 GHz, the distances are restricted to 0,75 m.}$
- 451

#### 452 **3.2 Acronyms**

- 453 AVF Antenna Validation Factor
- 454 CVF Chamber Validation Factor
- 455 CDF Cumulative Distribution Function
- 456 CISPR Comité International Spécial des Perturbations Radioélectriques
- 457 CLF Chamber Loading Factor
- 458 CW Continuous Wave
- 459 EM Electromagnetic
- 460 EMC Electromagnetic Compatibility
- 461 EMI Electromagnetic Interference
- 462 EUT Equipment Under Test
- 463 IEC International Electrotechnical Commission
- 464 IEEE Institute of Electrical and Electronics Engineers
- 465 IEV International Electrotechnical Vocabulary
- 466 IF Image Frequency
- 467 IFU Intrinsic Field Uncertainty
- 468 IL Insertion Loss
- 469 ISO International Standardisation Organisation
- 470 LUF Lowest Usable Frequency
- 471 OATS Open Area Test Site
- 472 PDF Probability Density Function